DE LA RECHERCHE À L'INDUSTRIE









ELECTROMAGNETIC FAULT INJECTION: TOWARDS A FAULT MODEL ON A 32-BIT MICROCONTROLLER

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MOTIVATIONS







- Security of microcontroller-based embedded systems against fault injection attacks
- Target: ARM Cortex-M3 microcontroller
- Fault injection means: Pulsed electromagnetic fault injection
- Theoretical attacks rely on an attacker's fault model
- Electromagnetic fault injection is quite recent
- Very few in-depths studies of the effects on complex systems
- → Better understanding of the effects of EM fault injection
- → Detailed fault model at a register-transfer level











- I. Experimental setup
- II. General approach
- III. Study of the injection parameters
- IV. Register-transfer level fault model
- V. Conclusion

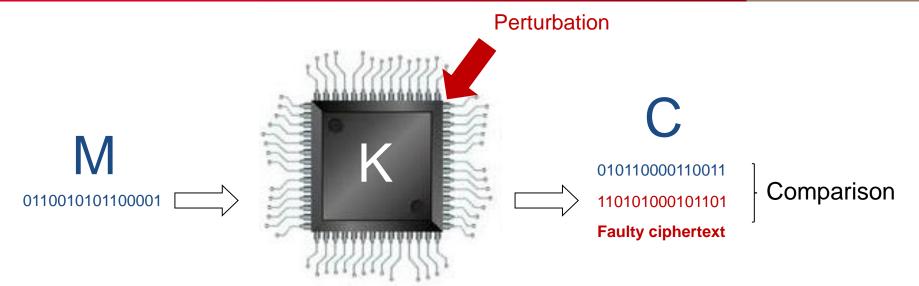


FAULT INJECTION ATTACKS









- Several physical ways to inject faults into a circuit's computation
- Necessary for an attacker to know the type of injected faults

Fault target	Data, instructions
Fault type	Bit flip, reset at 0, set at 1, stuck
Granularity	Bit, byte, word
Determinism	Deterministic, metastable, random
Temporal aspect	Single piece of data/instruction, multiple



EXPERIMENTAL SETUP

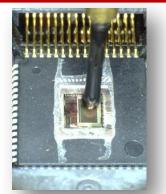






Pulsed electromagnetic fault injection

- Transient and local effect of the fault injection
- Standard circuits not protected against this technique
- Solenoid used as an injection antenna
- Up to 200V sent on the injection antenna, pulses width longer than 10ns



Microcontroller based on an ARM Cortex-M3

- Frequency 56 MHz
- -16/32 bits **Thumb2** RISC instruction set
- ARMv7-M modified Harvard architecture
- SWD link to debug the microcontroller



DETAILED EXPERIMENTAL PROTOCOL





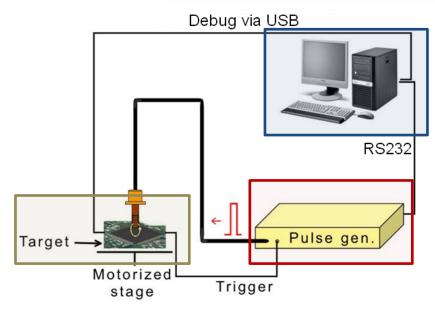


- Experiment driven by the computer
- Execution of a computation on the target device
- Sending of a voltage pulse
- Stop of the microcontroller
- Harvesting of the microcontroller's internal data
- Analysis of the obtained results

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Main experimental parameters

- Position of the injection antenna
- Electric parameters of the pulse
- Injection time of the pulse
- Executed code on the microcontroller











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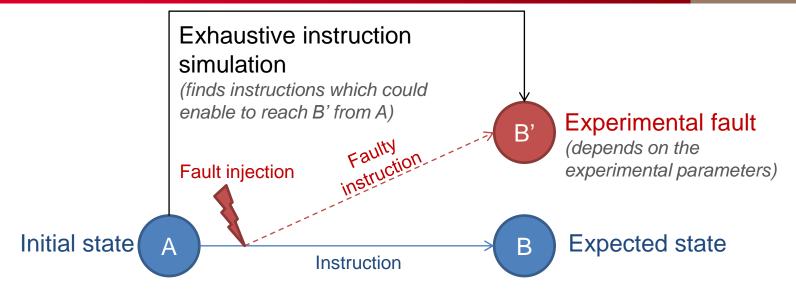


GENERAL APPROACH









Output pieces of data	Detail
R0 to R12	General-purpose registers
R13 (SP)	Stack pointer
R14 (LR)	Link register
R15 (PC)	Program counter
XPSR	Program Status Register - Flags - Details about the triggered interruptions - Details about the execution mode
Result	Memory address that contains the calculation's output



COO SIMULATION OF A FAULT MODEL



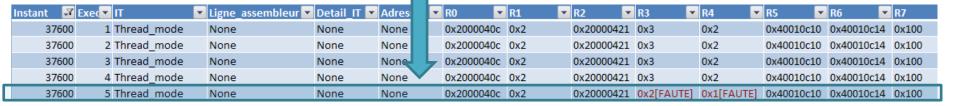




Instruction skip simulation

п	■ Ligne_assembleur	▼ Detail_IT	Adresse 💌	R0	R1 ▼	R2 ▼	R3 💌	R4	R5
Thread_mo	ode	None	None	0x2000040c	0x2	0x20000421	0x3	0x2	0x400
Thread_mo	ode 0x08000224 6803 LDR r3,[r0,#0	0x00] None	None	0x2000040c	0x2	0x20000421	0x7[FAUTE]	0x2	0x400
Thread_mo	ode 0x08000226 4423 ADD r3,r3,r4	None	None	0x2000040c	0x2	0x20000421	0x2[FAUTE]	0x2	0x400
Thread_mo	ode 0x08000228 6003 STR r3,[r0,#0	0x00] None	None	0x2000040c	0x2	0x20000421	0x2[FAUTE]	0x2	0x400
Thread_mo	ode 0x0800022A F1010101 ADD r1,r1	,#0x01 None	None	0x2000040c	0x2	0x20000421	0x4[FAUTE]	0x2	0x400
Thread_mo	ode 0x0800022E 2902 CMP r1,#0x0	2 None	None	0x2000040c	0x1[FAUTE]	0x20000421	0x1[FAUTE]	0x1[FAUTE]	0x400
Thread_mo	ode 0x08000230 DBF6 BLT 0x08000	None None	None	0x2000040c	0x2	0x20000421	0x3	0x2	0x400
Thread_mo	ode 0x08000220 F8524021 LDR r4,[r2	,r1,LSL #2] None	None	0x2000040c	0x2	0x20000421	0x2[FAUTE]	0x1[FAUTE]	0x400
Thread_mo	ode 0x08000224 6803 LDR r3,[r0,#0	0x00] None	None _	0x2000040c	0x2	0x20000421	0x3	0x2	0x400
Thread mo	ode 0x08000226 4423 ADD r3,r3,r4	None	None	0x2000040c	0x2	0x20000421	0x1[FAUTE]	0x2	0x400

Experimental measurements



■ Two lines are equal ⇔ R0 to R12 + XPSR + result + SP + PC are equal



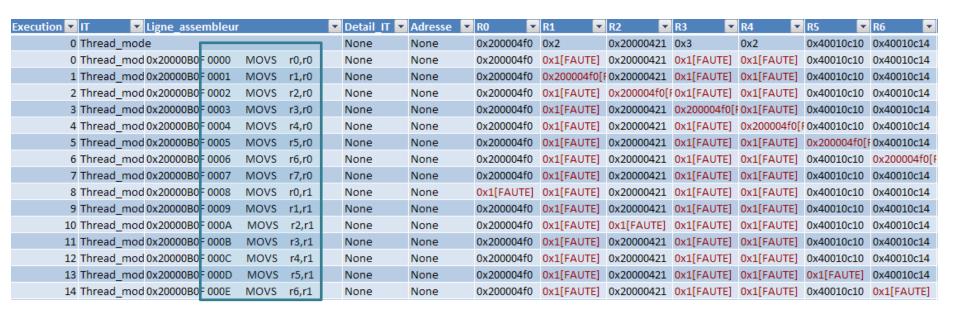
COO SIMULATION OF A FAULT MODEL







Example of simulation of a 16-bit instruction replacement



- Very long for an exhaustive simulation over the whole instruction set
- Two lines are equal ⇔ R0 to R12 + XPSR + result are equal









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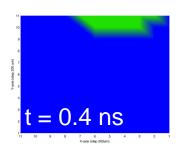
CO INFLUENCE OF THE ANTENNA'S POSITION

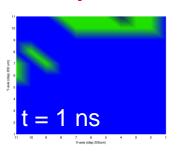


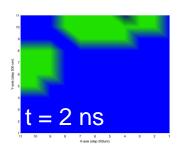


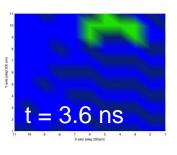


- Green: hardware interrupts have been triggered
- : faults on the output value have been obtained

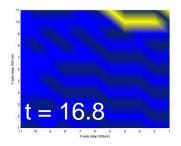


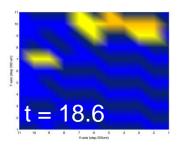


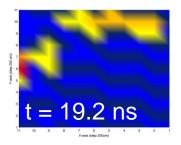


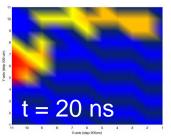


Frequency 56 MHz – Pulse width 10 ns – Pulse voltage 190V – Period 17ns









- Target instruction: single LOAD instruction that loads 0x12345678 into R8
- 20 ns time interval, by steps of 200 ps 3 mm square, by steps of 200 µm
- Variable increase of the Hamming weight of the loaded piece of data
- No fault on other registers than R8 (except for very few faults on R0)



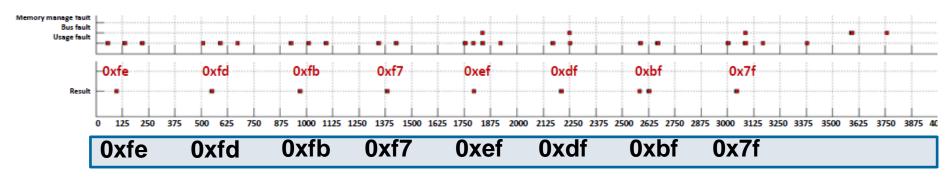
INFLUENCE OF THE INJECTION TIME







Example of temporal cartography on an addition loop



Observations:

- One power of two has not been added
- BusFault or UsageFault interrupts
- → Does our fault injection have an effect on the data flow or the control flow?

Test program:

loop to sum the elements of an array that contains eight powers of two 3.5 µs, by steps of 200 ps

Expected result: 0xFF

```
addition_loop:

ldr r4, [r2,r1, ls1 #2]; r4 = array[i]

ldr r3, [r0,#0]; r3 = result

add r3, r4; r3 = r3 + r4

str r3, [r0,#0]; result = r3

add r1, r1, #1; r1 = r1 + 1

cmp r1, #8; r1 == 8?

blt addition_loop
```



COO INFLUENCE OF THE PULSE'S VOLTAGE







LDR R4, PC#44 with 0x12345678 at the address PC#44

Pulse voltage	Output value	Occurrence rate
172V	1234 5678	100 %
174V	9 234 5678	73 %
176V	FE34 5678	30 %
178V	FFF4 5678	53 %
180V	FFFD 5678	50 %
182V	FFFF 7F 78	46 %
184V	FFFF FFFB	40 %
186V	FFFF FFFF	100 %

- Simulation : corresponds to no instruction replacement
- Looks like a set at 1 fault model on the Flash memory data transfers
- Possible precharge of the data bus on this architecture









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CEZ FAULTS ON THE CONTROL FLOW







- Experiments with a sequence of NOP (BF 00)
- Four kinds of faults
 - Fault on R7
 - The program does not stop
 - UsageFault exceptions (Invalid Instruction / No Coprocessor)
 - Fault on R0
- Sometimes a modification of the number of executed cycles
- Simulation on the ISA: some instructions can explain the results
- Some faults only equivalent to a STR R0, [R0, #0] instruction

NOP - BF00 1011 1111 0000 0000 **NOP - BF00** 1011 1111 0000 0000

STR R0, [R0, #0] - 6000 0110 0000 0000 0000 **NOP - BF00** 1011 1111 0000 0000

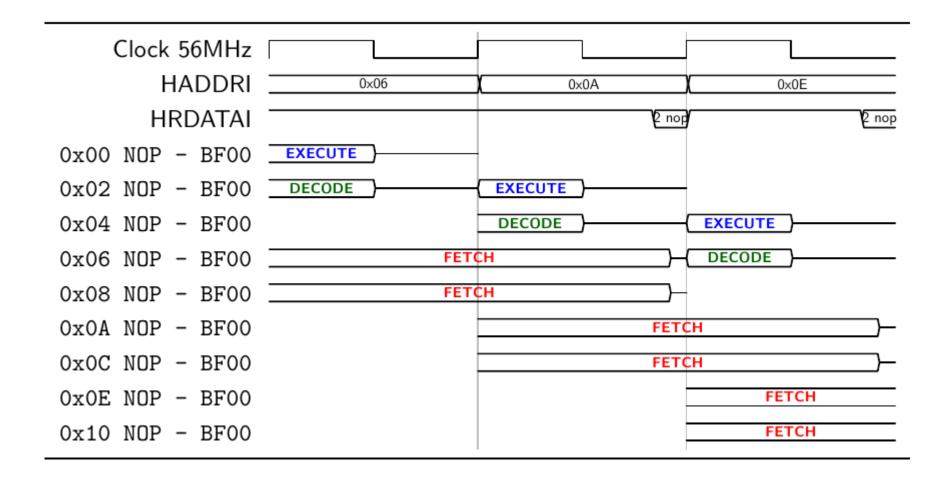








Normal behaviour



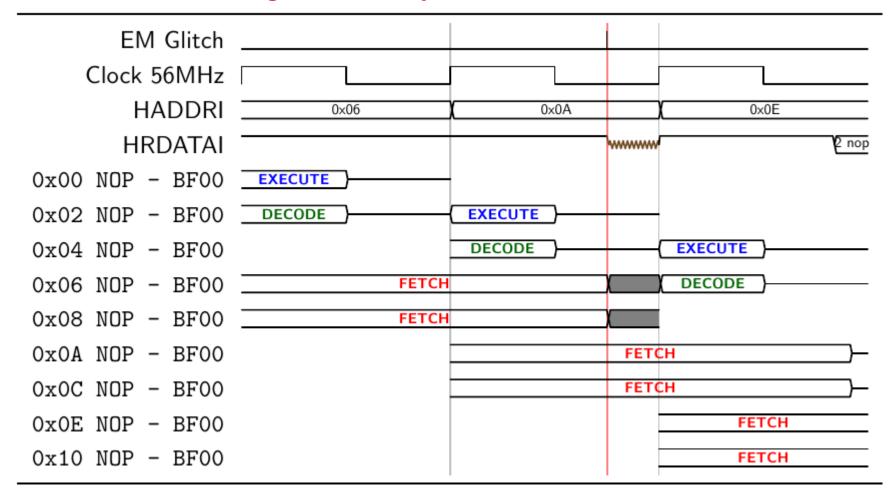








With an electromagnetic fault injection





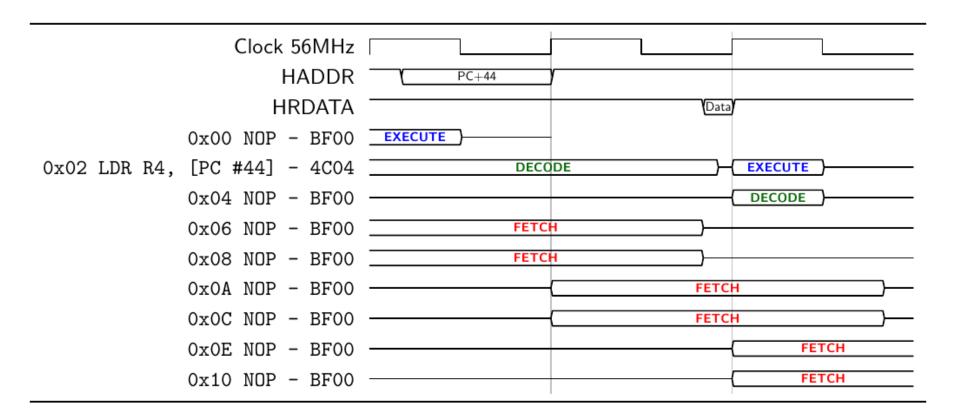
COO DATA LOAD FROM THE FLASH MEMORY







Normal behaviour





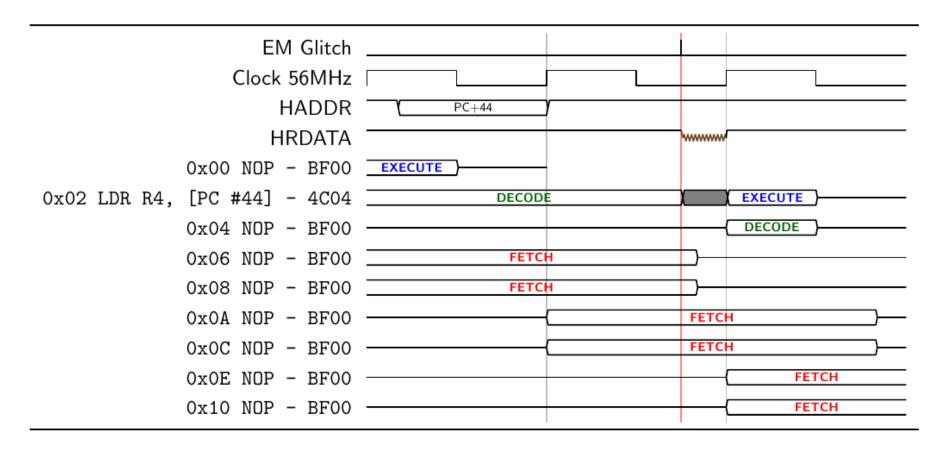
COO DATA LOAD FROM THE FLASH MEMORY







With an electromagnetic fault injection





OVERVIEW OF THE DEFINED FAULT MODEL







→ Possible to fault the transfers from the Flash memory

Consequences regarding the instruction flow

- Instructions replacements
- Instruction skips under certain conditions (~ 20-30% of time)
- Some instructions may be more sensitive than others
- Some registers seem to be more sensitive than others

Consequences regarding the data flow

- Corruption of the LOAD instructions from the Flash memory (encryption keys,...)
- Some metastability phenomena, but deterministic under some conditions
- Faulty values with higher Hamming weight (on this architecture)









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COORCLUSION AND PERSPECTIVES







- A first attempt of fault model for EM fault injection on a 32-bit μC
- Corruption of the transfers from the Flash memory on the buses
- The obtained effects seem very similar to the ones obtained with clock glitches or other fault injection means
- Similar effects obtained previously on a very different architecture (Atmel AVR ATmega128 8-bit microcontroller)
- Possibility to perform instruction skips under some specific conditions

Perspectives

- Use more advanced debug techniques to understand better instruction replacements
- Define a higher-level fault model that can be used for theoretical attacks





Any questions?